

Abstract

This inspection device inspects a shell structure in which a section where electrical conduction is established between a conductive portion of a substrate and a jig contact portion is sealed. The inspection device comprises: a housing; a probe that contacts an electrode of the jig in electrical conduction with the contact portion, inside the housing; a temperature adjustment medium circulation unit that supplies and discharges a temperature adjustment medium into and out of the housing; and a control unit. The control unit controls: (A) a step for placing the shell structure with the probe and the electrode being in contact with each other; (B) a step for adjusting the temperature of the shell structure by supplying the temperature adjustment medium from the temperature adjustment medium circulation unit and immersing at least a portion of the shell structure in the temperature adjustment medium; and (C) a step for inspecting the substrate of the shell structure via the probe.